Docket Number: 081468-0306518

Client Reference: P-0365.010-US



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

ARIE JEFFREY DEN BOEF, et al.

Group Art Unit: (Unknown)

Application No.: 10/696,742

Examiner: (Unknown)

Filed: October 30, 2003

Confirmation No.: (Unknown)

For: TEST PATTERN, INSPECTION METHOD, AND DEVICE MANUFACTURING

METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449s. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date of this non-CPA application. No certification or fee is required.

The reference(s) was/were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully Submitted,

Kerry T. Hartman

Registration Number 41818

Date: November 19, 2003 PILLSBURY WINTHROP LLP Telephone: (703) 905-2000 Facsimile: (703) 905-2500

P.O. Box 10500 McLean, VA 22102

_ 					_						~							
FORM P#O-					O	IPE	_	Atty.	N	1#				- -	Client	Ref.		
(PW FORM I		nent of Commerce		/		ر	<u>}</u>	Dkt. No.	1		, kg			40	8. N	. Çiç ∙ ÿ		
		rademark Office		PARENT)V	1 9 2003	<u>*</u>)											
				(A)		3408	9		6	30651	18				P-03	65.0	10-US	
INFORMA	TIO	N DISCLOSURE S	τΔΤί	=MFN	<i>⁄₽/</i>	DEMAN		Applican	_			Fet	al.		<u> . 55</u>			
BY APPLI			,,,,,,,		•			· · ·										
								Appln. N	0.:	10/69	6,7	1 2						
							٦	Filing Da	ite:	Octol	ber	30, 2	003					
Date: Nove	embe	er 19, 2003	Page	1	of	1	<u> L</u>	Examine	er:	(Unkr	owi	າ)	G	rou	ıp Art Uı	nit:		
U.S. PATE	NT D	OCUMENTS																
Examiner'		Document		Date		Name							Cla	ass			Filing	
S		Number		1	Υ	(Family N	lame	of First In	ive	ntor)					Class	3	Date	
Initials*	-			YY									+		_		(if appropi	nate)
	AR	US-2002/0041373 A	11			LITTAU 6							+		_		<u> </u>	
·		6,458,605 B1		10/20	02	STIRTO	<u> </u>										<u> </u>	
	CR				\dashv								_				<u> </u>	
·	DR 												-					
· · · · · · · · · · · · · · · · · · ·	ER_												+	-	<u> </u>			
	FR			ļ	_								+		<u> </u>			
	GR				_			···-					-		_		<u> </u>	
· · · · · · · · · · · · · · · · · · ·	HR 				-										-	-	ļ <u>.</u>	
	IR				\dashv												 	
+	JR 				\dashv								+				 	
· +	KR												-				<u> </u>	
	LR						-						-				 	
	MR_												\dashv				 	—
	NR			<u> </u>										т			<u> </u>	
FOREIGN	PATE	ENT DOCUMENTS		<u>, a i</u>		or, y of b	1			Prog. J	¥ ;.	<u> </u>	i in		English Abstract		Translati Readily	ion
		Document	Date MM/Y	~~~	Co	ountry	Inver	ntor Name	е								Available	3
		Number												ŀ	Enclosed	No	Enclose	TNO
	<u> </u>	NO 00 004007 A	04/00	00		\	0.415	IED		+-				-		1,40	Litologe	100
	_	WO 03 001297 A	01/20		PC		MIEH			- 				_	X X	ļ.,	1	\vdash
1		WO 02 077570 A	10/20 03/20		PC	•		SH et al.						\rightarrow	^ X	ļ	+	\vdash
	•	WO 02 21075 A EP 0 985 977 A	03/20		PC EF		LITT							$\overline{}$	^ X	 	+	+
		WO 02 070985 A			PC		†	INER et a	<u> </u>					_	^ X		 	+-
· ·			09/20		PC			MOND						$\overline{}$	<u>^ </u>		 	\vdash
	TR UR	WO 02 065545 A2	08/20	02	-		SEZ	GINER						\dashv	^	<u> </u>	 	\vdash
										+	-			\dashv			 	\vdash
	<u>VR</u> WR				\vdash		+	<u> </u>						\dashv		 	 	+
· · · · · · · · · · · · · · · · · · ·	<u>WR</u> XR		-		\vdash		 	· · · · · · · · · · · · · · · · · · ·						\dashv		<u> </u>		+-
	ΛR	<u> </u>	L		<u> </u>	······································	<u> </u>	Data C-		4052						<u> </u>	1	<u> —</u>
Examiner	D.	Initial if citation consid		b.o.4b.c.		not c:t-t:-	n ic !-	Date Co				220	00 5)-c-	u line th-	oua-	oitatio =	
*EXAMINEI		initial if citation considered.												ıı av	w iii le u ifi	ouyn 	UIIAIIUI)	



PTO/SB/08b(05-03)

Approved for use through 04/30/2003. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for	r form 1449B/PTO			Complete if Known					
				Application Number	10/696,742				
	RMATION DI			Filing Date	10/30/2003				
STAT	EMENT BY	APPLI	CANT	First Named Inventor	ARIE JEFFREY DEN BOEF				
				Art Unit	0000				
	(Use as many sheets as	necessary)	Examiner Name	(UNKNOWN)				
Sheet	1	of	1	Attorney Docket Number	081468-0306518				

	NON PATENT LITERATURE DOCUMENTS								
Examiner Initials*	Cite No.1								
	9	K.C. HICKMAN ET AL., "Use of Diffracted Light From Latent Images to Improve Lithography Control," Journal of Vacuum Science & Technology B, American Vacuum Society (USA), Vol. 10 (No. 5), p. 2259-2266, (Sept/Oct 1992).							
	10	E.L. RAAB ET AL., "Analyzing Deep-UV Lens Aberrations Using Aerial Image and Latent Image Metrologies," SPIE, SPIE (USA), 2-4 March, 1994, p. 550-565, (vol. 2197).							
	11	CHRISTOPHER J. RAYMOND ET AL., "Multiparameter Grating Metrology Using Optical Scatterometry," Journal of Vacuum Science & Technology B, 2nd ed., American Institute of Physics for the American Vacuum Society (USA), Vol. 15 (No. 2), p. 361-368, (Mar/Apr 1997).							
	12	XINHUI NIU ET AL., "Specular Spectroscopic Scatterometry in DUV Lithography," Part of the SPIE Conference on Metrology, Inspection, and Process Control for Microlithography XIII, SPIE (Santa Clara, CA, USA), p. 159-168, (March 1999) (vol. 3677).							
· · · · · · · · · · · · · · · · · ·		·							

		Y	
Examiner	Date		
Signature	Considered		
Signature	 Considered		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450.

DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.